

6249825 0015953 2 MITSUBISHI LSIs
**MH1M09A0J-8,-10,-12/
 MH1M09A0JA-8,-10,-12**

FAST PAGE MODE 1048576-WORD BY 9-BIT DYNAMIC RAM

MITSUBISHI (MEMORY/ASIC) 29E D

DESCRIPTION

The MH1M09A0J, JA is 1048576 word x 9 bit dynamic RAM and consists of nine industry standard 1M x 1 dynamic RAMs in SOJ.

The mounting of SOJ on a single in-line package provides any application where high densities and large quantities of memory are required.

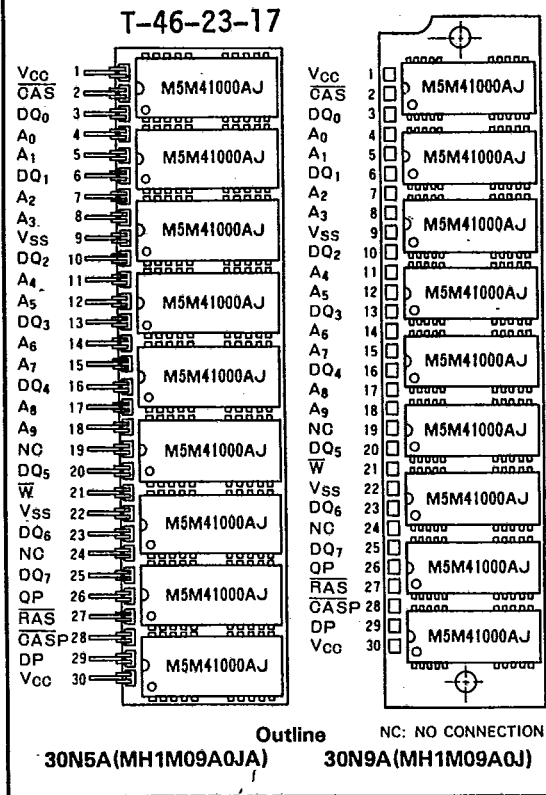
FEATURES

● Performance ranges

Type name	Access time (max) (ns)	Cycle time (min) (ns)	Power dissipation (typ) (mW)
MH1M09A0J-8 MH1M09A0JA-8	80	160	1800
MH1M09A0J-10 MH1M09A0JA-10	100	190	1575
MH1M09A0J-12 MH1M09A0JA-12	120	220	1350

- Utilizes industry standard 1M RAMs in SOJ
- 30 pins Single In-line Package
- Single +5V (±10%) supply operation
- Low standby power dissipation 24.8mW (max) CMOS input level
- Low operation power dissipation:
 MH1M09A0J-8, MH1M09A0JA-8 3.46W (max)
 MH1M09A0J-10, MH1M09A0JA-10 . . . 2.97W (max)
 MH1M09A0J-12, MH1M09A0JA-12 . . . 2.48W (max)
- All inputs are directly TTL compatible
- All outputs are three-state and directly TTL compatible
- Includes (0.22µF x 9) decoupling capacitors
- 512 refresh cycles every 8ms, A₉ Pin is not need for refresh
- Common $\overline{\text{CAS}}$ control for eight common Data-In and Data-Out lines.
- Separate CAS ($\overline{\text{CASP}}$) control for one separate pair of Data-In and Data-Out lines.
- The common I/O feature dictates the use of only early write operation to prevent contention on Data-In and

PIN CONFIGURATION (TOP VIEW)

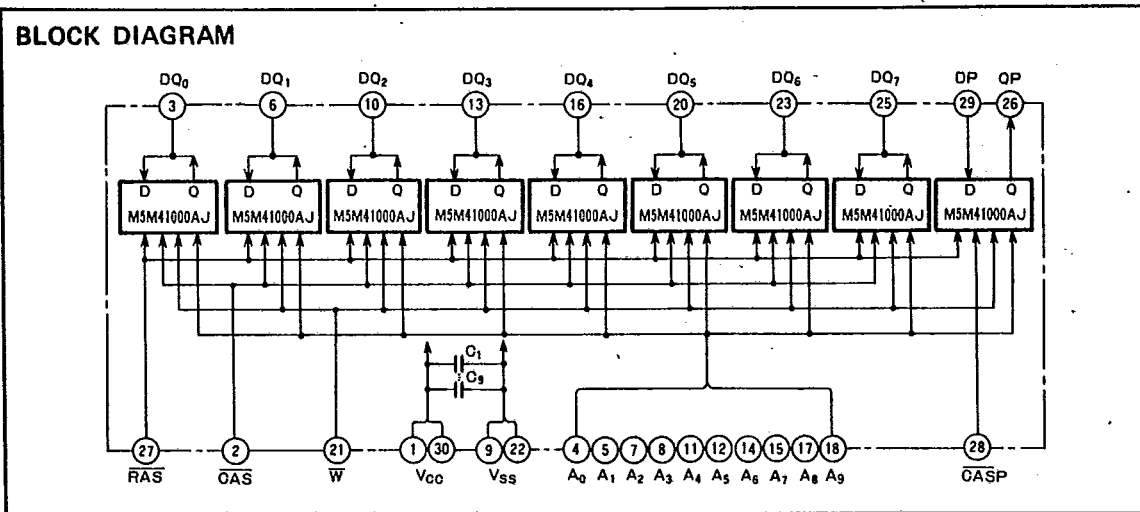


- Data-Out.
- Bit nine (DP, QP) controlled by $\overline{\text{CASP}}$ is generally used for parity.

APPLICATION

Main memory unit for computers, Refresh memory.

BLOCK DIAGRAM



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The MH1M09A0J, JA provide, in addition to normal read, and early write operations, a number of other functions, e.g., fast-page mode. RAS-only refresh and CAS before RAS refresh. The input conditions for each are shown in Table 1.

Table 1 Input conditions for each mode

Operation	Inputs					Input/Output		Refresh	Remark
	$\overline{\text{RAS}}$	$\overline{\text{CAS}}$	$\overline{\text{W}}$	Row address	Column address	Input	Output		
Read	ACT	ACT	NAC	APD	APD	OPN	VLD	YES	Fast page mode identical
Early write	ACT	ACT	ACT	APD	APD	VLD	OPN	YES	
RAS-only refresh	ACT	NAC	DNC	APD	DNC	DNC	OPN	YES	
Hidden refresh	ACT	ACT	DNC	DNC	DNC	OPN	VLD	YES	
CAS before RAS refresh	ACT	ACT	DNC	DNC	DNC	DNC	OPN	YES	
Standby	NAC	DNC	DNC	DNC	DNC	DNC	OPN	NO	

Note : ACT: active, NAC: nonactive, DNC: don't care, VLD: valid, APD: applied, OPN: open

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ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	conditions	Ratings	Unit
V _{CC}	Supply voltage		-1~7	V
V _I	Input voltage	With respect to V _{SS}	-1~7	V
V _O	Output voltage		-1~7	V
I _O	Output current		50	mA
P _d	Power dissipation	T _a =25°C	9	W
T _{opr}	Operating temperature		0~70	°C
T _{stg}	Storage temperature		-40~125	°C

RECOMMENDED OPERATING CONDITIONS (T_a=0~70°C, unless otherwise noted) (Note 1)

Symbol	Parameter	Limits			Unit
		Min	Norm	Max	
V _{CC}	Supply voltage	4.5	5	5.5	V
V _{SS}	Supply voltage	0	0	0	V
V _{IH}	High-level input voltage, all inputs	2.4		6.5	V
V _{IL}	Low-level input voltage all inputs	-1.0		0.8	V

Note 1: All voltage values are with respect to V_{SS}.**ELECTRICAL CHARACTERISTICS** (T_a=0~70°C, V_{CC}=5V±10%, V_{SS}=0V, unless otherwise noted) (Note 2)

Symbol	Parameter	Test conditions	Limits			Unit	
			Min	Typ	Max		
V _{OH}	High-level output voltage	I _{OH} =-5mA	2.4		V _{CC}	V	
V _{OL}	Low-level output voltage	I _{OL} =4.2mA	0		0.4	V	
I _{OZ}	Off-state output current	Q floating 0V ≤ V _{OUT} ≤ 5.5V	-20		20	μA	
I _I	Input current	0V ≤ V _{IH} ≤ 6.5V, Other input pins=0V	-90		90	μA	
I _{CC1(AV)}	Average supply current from V _{CC} operating (Note 3, 4)	MH1M09A0-8	R _{AS} , C _{AS} cycling			630	mA
		MH1M09A0-10	t _{RO} =t _{WC} =min, output open			540	
		MH1M09A0-12				450	
I _{CC2}	Supply current from V _{CC} , standby	R _{AS} =C _{AS} =V _{IH} , output open			18	mA	
		R _{AS} =C _{AS} ≥V _{CC} -0.5, output open			4.5		
I _{CC3(AV)}	Average supply current from V _{CC} refreshing (Note 3)	MH1M09A0-8	R _{AS} cycling, C _{AS} =V _{IH}			630	mA
		MH1M09A0-10	t _{RO} =min, output open			540	
		MH1M09A0-12				450	
I _{CC4(AV)}	Average supply current from V _{CC} Fast page mode (Note 3, 4)	MH1M09A0-8	R _{AS} =V _{IL} , C _{AS} =cycling			540	mA
		MH1M09A0-10	t _{PO} =min, output open			450	
		MH1M09A0-12				360	
I _{CC6(AV)}	Average supply current from V _{CC} C _{AS} before R _{AS} refresh mode (Note 3)	MH1M09A0-8	C _{AS} before R _{AS} refresh cycling			630	mA
		MH1M09A0-10	t _{RO} =min, output open			540	
		MH1M09A0-12				450	

Note 2: Current flowing into an IC is positive, out is negative.

3: I_{CC1(AV)}, I_{CC3(AV)}, I_{CC4(AV)} and I_{CC6(AV)} are dependent on cycle rate. Maximum current is measured at the fastest cycle rate.4: I_{CC1(AV)} and I_{CC4(AV)} are dependent on output loading. Specified values are obtained with the output open.**CAPACITANCE** (T_a=0~70°C, V_{CC}=5V±10%, V_{SS}=0V, unless otherwise noted)

Symbol	Parameter	Test conditions	Limits			Unit
			Min	Typ	Max	
C _{I(A)}	Input capacitance, address inputs	V _I =V _{SS} f=1MHz V _I =25mVrms			60	pF
C(DQ)	Data input/data output capacitance				17	pF
C _{I(W)}	Input capacitance, write control input				75	pF
C _{I(RAS)}	Input capacitance, R _{AS} input				75	pF
C _{I(CAS)}	Input capacitance, C _{AS} input				70	pF
C _{I(CASP)}	Input capacitance, C _{ASP} input				15	pF
C _{I(OP)}	Input capacitance				15	pF
C _{O(OP)}	Output capacitance		V _O =V _{SS} , f=1MHz, V _I =25mVrms			12

SWITCHING CHARACTERISTICS ($T_a = 0 \sim 70^\circ\text{C}$, $V_{CC} = 5V \pm 10\%$, $V_{SS} = 0V$, unless otherwise noted) (Note 5)

Symbol	Parameter	Limits						Unit
		MH1M09A0-8		MH1M09A0-10		MH1M09A0-12		
		Min	Max	Min	Max	Min	Max	
t_{OAO}	Access time from $\overline{\text{CAS}}$ (Note 6, 7)		20		25		30	ns
t_{RAO}	Access time from $\overline{\text{RAS}}$ (Note 6, 8)		80		100		120	ns
t_{CAA}	Column address access time (Note 6, 9)		40		50		60	ns
t_{CPA}	Access time from $\overline{\text{CAS}}$ precharge (Note 6, 10)		45		55		65	ns
t_{OLZ}	Output low impedance time from $\overline{\text{CAS}}$ low (Note 6)	5		5		5		ns
t_{OFF}	Output disable time after $\overline{\text{CAS}}$ high (Note 11)	0	20	0	25	0	30	ns

- Note 5: An initial pause of 500 μ s is required after power-up followed by any 8 $\overline{\text{RAS}}$ or $\overline{\text{RAS}}/\overline{\text{CAS}}$ cycles before proper device operation is achieved. Note that $\overline{\text{RAS}}$ may be cycled during the initial pause. And any 8 $\overline{\text{RAS}}$ or $\overline{\text{RAS}}/\overline{\text{CAS}}$ cycles are required after prolonged periods of $\overline{\text{RAS}}$ inactivity before proper device operation is achieved.
- 6: Measured with a load circuit equivalent to 2TTL loads and 100pF.
- 7: Assume that $t_{RCD(\text{max})} \leq t_{RCD}$ and $t_{RAD(\text{max})} \geq t_{RAD}$.
- 8: Assume that $t_{RCD} \leq t_{RCD(\text{max})}$ and $t_{RAD} \leq t_{RAD(\text{max})}$.
- 9: Assume that $t_{RCD} - t_{RAD} \leq t_{CAA(\text{max})} - t_{CAC(\text{max})}$ and $t_{RCD} \geq t_{RCD(\text{max})}$.
- 10: Assume that $t_{CP} \leq t_{CP(\text{max})}$ and $t_{ASC} \geq t_{ASC(\text{max})}$.
- 11: $t_{OFF(\text{max})}$ define the time at which the output achieves the high impedance state ($I_{OUT} \leq \pm 20\mu\text{A}$) and are not reference to $V_{OH(\text{min})}$ or $V_{OL(\text{max})}$.

TIMING REQUIREMENTS (For Read, Early Write, Fast-Page Mode Cycles)

($T_a = 0 \sim 70^\circ\text{C}$, $V_{CC} = 5V \pm 10\%$, $V_{SS} = 0V$, unless otherwise noted) (Note 12, 13)

Symbol	Parameter	Limits						Unit
		MH1M09A0-8		MH1M09A0-10		MH1M09A0-12		
		Min	Max	Min	Max	Min	Max	
t_{REF}	Refresh cycle time		8		8		8	ms
t_{RP}	$\overline{\text{RAS}}$ high pulse width	70		80		90		ns
t_{RCD}	Delay time, $\overline{\text{RAS}}$ low to $\overline{\text{CAS}}$ low (Note 14)	25	60	25	75	25	90	ns
t_{CRP}	Delay time, $\overline{\text{CAS}}$ high to $\overline{\text{RAS}}$ low (Note 15)	10		10		10		ns
t_{CPN}	$\overline{\text{CAS}}$ high pulse width (Note 16)	35		35		35		ns
t_{RAD}	Column address delay time from $\overline{\text{RAS}}$ low (Note 17)	20	40	20	50	20	60	ns
t_{ASR}	Row address setup time before $\overline{\text{RAS}}$ low	0		0		0		ns
t_{ASO}	Column address setup time before $\overline{\text{CAS}}$ low (Note 18)	0	15	0	20	0	25	ns
t_{RAH}	Row address hold time after $\overline{\text{RAS}}$ low	15		15		15		ns
t_{CAH}	Column address hold time after $\overline{\text{CAS}}$ low or $\overline{\text{W}}$ low	20		20		20		ns
t_T	Transition time (Note 19)	3	50	3	50	3	50	ns

- Note 12: The timing requirements are assumed $t_T = 5\text{ns}$.
- 13: $V_{IH(\text{min})}$ and $V_{IL(\text{max})}$ are reference levels for measuring timing of input signals.
- 14: $t_{RCD(\text{max})}$ is specified as a reference point only. If t_{RCD} is less than $t_{RCD(\text{max})}$, access time is t_{RAC} . If t_{RCD} is greater than $t_{RCD(\text{max})}$, access time is defined as t_{CAC} and t_{CAA} as shown in note 7, 9.
- 15: t_{CRP} requirement is applicable for all $\overline{\text{RAS}}/\overline{\text{CAS}}$ cycles.
- 16: $t_{CPN(\text{min})}$ is specified as $t_{CPN(\text{min})} = t_{RCD(\text{min})} + t_{CRP(\text{min})}$ except for t_{CP} of fast page mode cycle.
- 17: $t_{RAD(\text{max})}$ is specified as a reference point only. If $t_{RAD} \geq t_{RAD(\text{min})}$, access time is assumed by t_{CAA} for read cycle.
- 18: $t_{ASC(\text{max})}$ is specified as a reference point only of address access time.
- 19: t_T is measured between $V_{IH(\text{min})}$ and $V_{IL(\text{max})}$.

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Read and Refresh Cycles

Symbol	Parameter	Limits						Unit
		MH1M09A0-8		MH1M09A0-10		MH1M09A0-12		
		Min	Max	Min	Max	Min	Max	
t _{RC}	Read cycle time	160		190		220		ns
t _{RAS}	RAS low pulse width	80	10000	100	10000	120	10000	ns
t _{CAS}	CAS low pulse width	20	10000	25	10000	30	10000	ns
t _{CSH}	CAS hold time after RAS low	80		100		120		ns
t _{RSH}	RAS hold time after CAS low	20		25		30		ns
t _{ROS}	Read setup time before CAS low	0		0		0		ns
t _{ROH}	Read hold time after CAS high (Note 20)	0		0		0		ns
t _{RRH}	Read hold time after RAS high (Note 20)	10		10		10		ns
t _{RAL}	Column address to RAS setup time	40		50		60		ns
t _{RPO}	Precharge to CAS active time	0		0		0		ns

Note 20: Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.

Write Cycle (Early Write)

Symbol	Parameter	Limits						Unit
		MH1M09A0-8		MH1M09A0-10		MH1M09A0-12		
		Min	Max	Min	Max	Min	Max	
t _{WC}	Write cycle time	160		190		220		ns
t _{RAS}	RAS low pulse width	80	10000	100	10000	120	10000	ns
t _{CAS}	CAS low pulse width	20	10000	25	10000	30	10000	ns
t _{CSH}	CAS hold time after RAS low	80		100		120		ns
t _{RSH}	RAS hold time after CAS low	20		25		30		ns
t _{WCS}	Write setup time before CAS low (Note 21)	0		0		0		ns
t _{WCH}	Write hold time after CAS low	15		20		25		ns
t _{WP}	Write pulse width	15		20		25		ns
t _{DS}	Data setup time	0		0		0		ns
t _{DH}	Data hold time after CAS low	15		20		25		ns

Note 21: When t_{WCS} < t_{WCS(min)}, Data input will contend with the data output because of the common I/O feature.

Fast Page Mode Cycle (Read, Early write Cycles)

Symbol	Parameter	Limits						Unit
		MH1M09A0-8		MH1M09A0-10		MH1M09A0-12		
		Min	Max	Min	Max	Min	Max	
t _{PC}	Fast page mode cycle time	50		60		70		ns
t _{RAS}	RAS low pulse width for read, write cycle	130	100000	160	100000	185	100000	ns
t _{CAS}	CAS low pulse width for read cycle	20	10000	25	10000	30	10000	ns
t _{CP}	CAS high pulse width (Note 22)	10	25	10	25	15	30	ns
t _{RSH}	RAS hold time after CAS low	20		25		30		ns

Note 22: t_{CP(max)} is specified as a reference point only. If t_{CP(max)} ≤ t_{CP}, access time is assumed by t_{CAC}.

CAS before RAS Refresh Cycle (Note 23)

Symbol	Parameter	Limits						Unit
		MH1M09A0-8		MH1M09A0-10		MH1M09A0-12		
		Min	Max	Min	Max	Min	Max	
t _{CSR}	CAS setup time for CAS before RAS refresh	10		10		10		ns
t _{CHR}	CAS hold time for CAS before RAS refresh	15		20		25		ns
t _{RPO}	Precharge to CAS active time	0		0		0		ns

Note 23: Eight or more CAS before RAS cycles is necessary for proper operation of CAS before RAS refresh mode.

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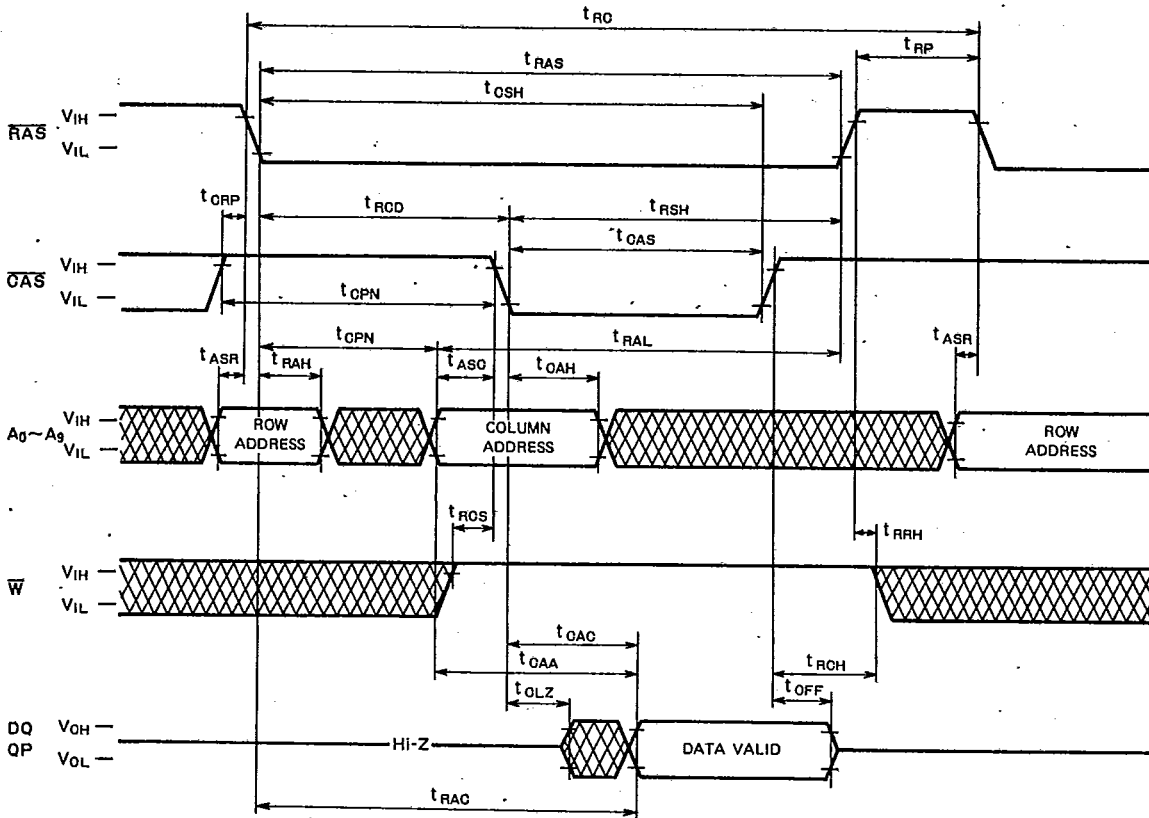
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Timing Diagrams (Note 24)

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Read Cycle

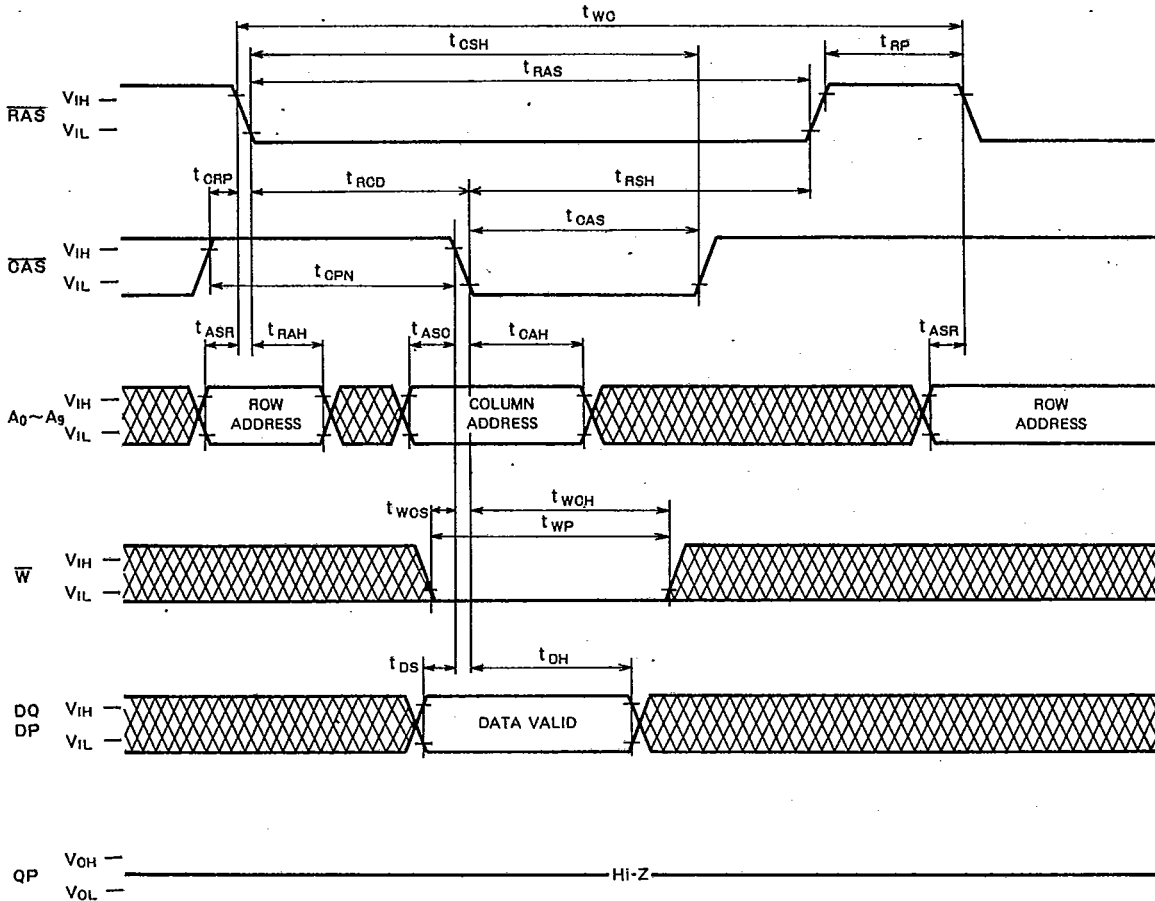


Note 24  Indicates the don't care input.

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Early Write Cycle



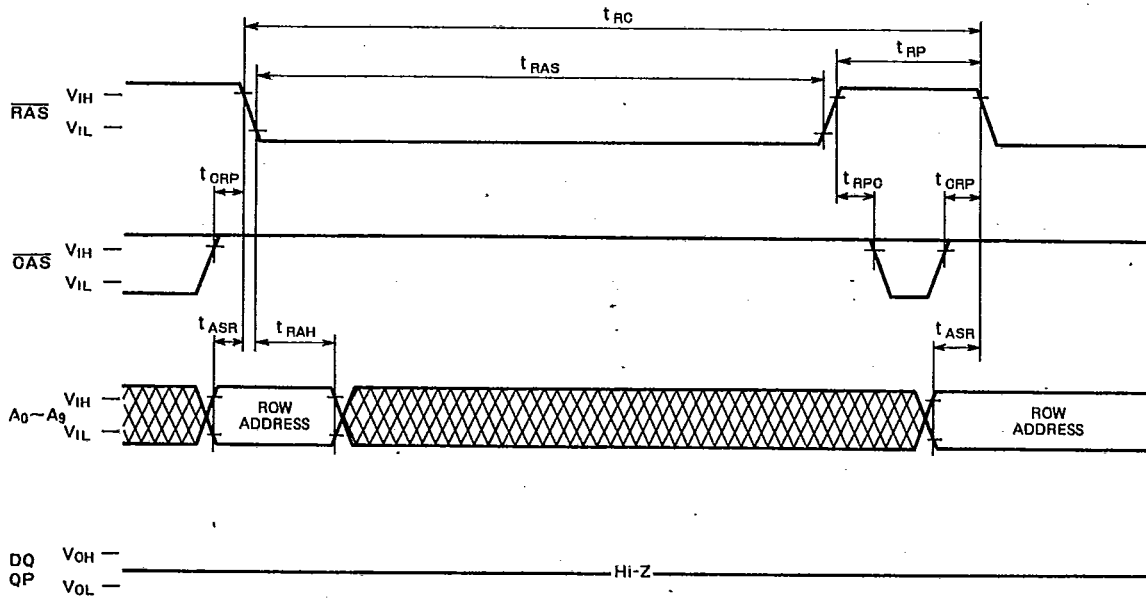
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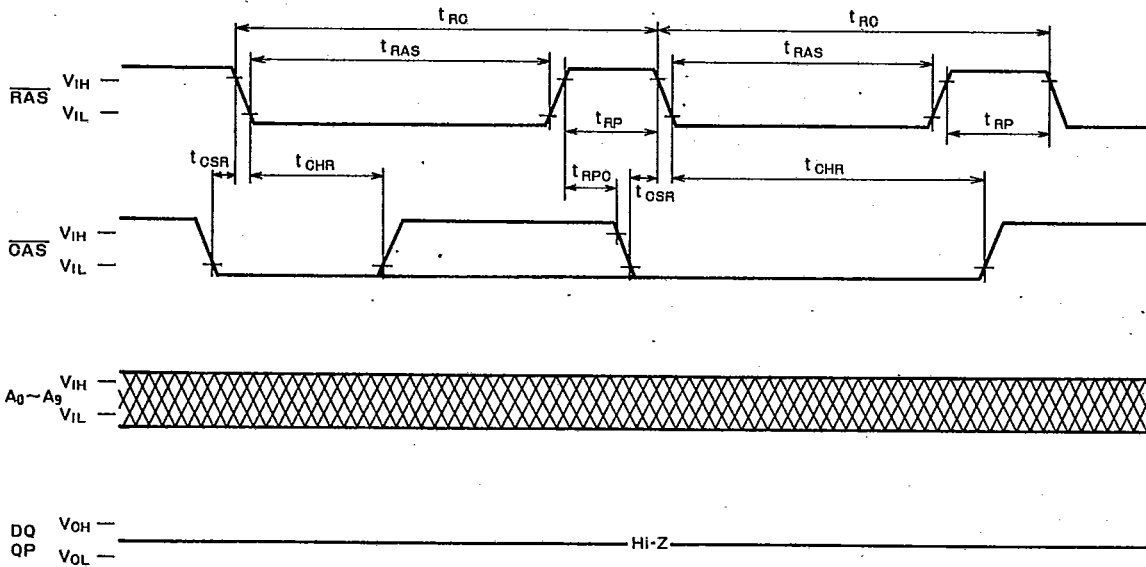
RAS only Refresh Cycle (Note 25)

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Note 25: \bar{W} , DP = don't care, A_9 may be V_{IH} or V_{IL} .

CAS before RAS Refresh Cycle (Note 26)

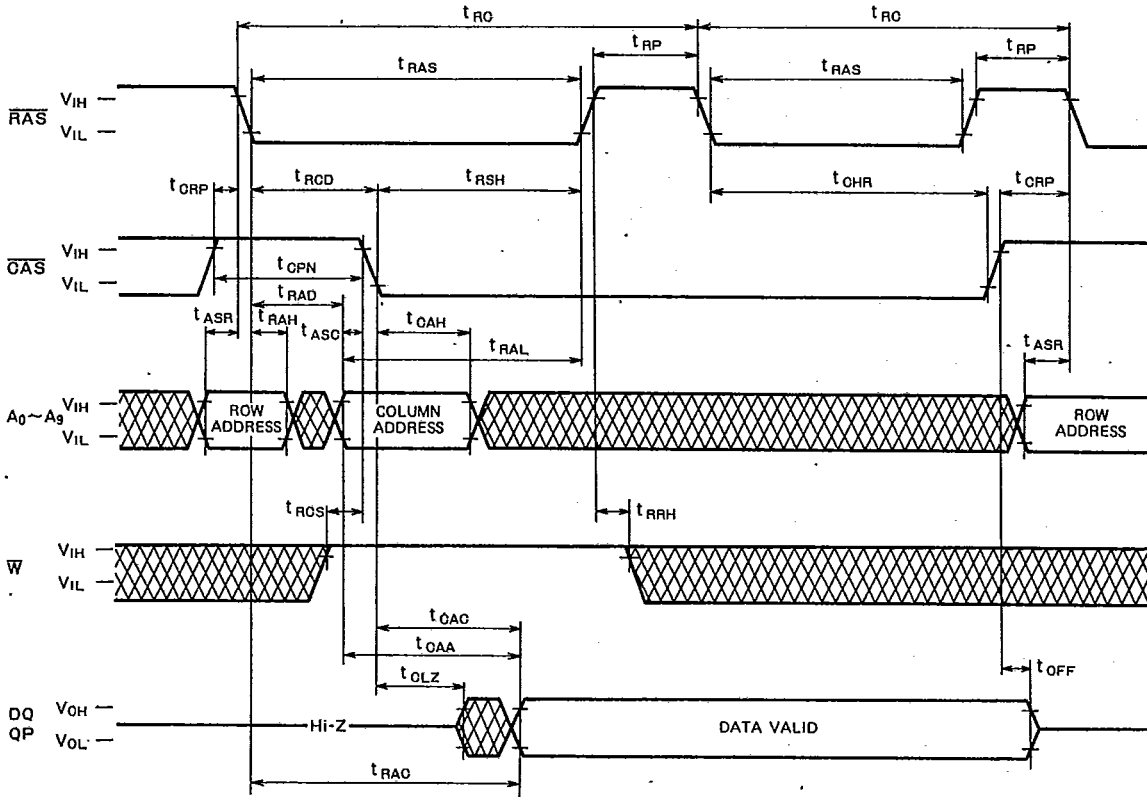


Note 26: \bar{W} , DP = don't care

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Hidden Refresh Cycle



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Fast-Page-Mode Early Write Cycle

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